

Amendments to the Specification:

Please amend the title of the invention as follows:

DEFECTIVE PIXEL DETECTOR, DEFECTIVE PIXEL-DETECTION PROCESS, AND IMAGING SYSTEM FOR DETECTING A PIXEL TO BE FACTORED OUT AMONG A PLURALITY OF PIXELS BASED ON A PIXEL TO BE INSPECTED AND A NEIGHBORING PIXEL AROUND THE PIXEL TO BE INSPECTED

And please amend the paragraph on page 10, line 20 to page 11, line 19 as follows:

Embodiments of the invention are now explained with reference to the drawings. FIG. 1 is a block diagram illustrative of the arrangement of the first embodiment according to the invention. In FIG. 1, an output signal from a solid-state imaging device 101 such as a CCD is converted by an A/D converter 102 into a digital signal that is then loaded in a latch 103. The latch 103 comprises a delay unit D, a line memory, etc., and is adapted to hold the pixel data demanded by a defective pixel detection algorithm. A latch 103', too, comprises a delay unit D, a line memory,

etc., and is adapted to receive an output digital signal from the A/D converter 102. A normal pixel detection block 104 is adapted to receive an output signal from the latch 103' to make simple determination of whether the pixel to be inspected is a normal one or a possibly defective one, and send out the result of determination to a defective pixel detection block 105. The defective pixel detection block 105 makes determination of whether only a pixel - that is not determined by the normal pixel detection block ~~104~~ 104 as normal - is normal or defective, using the pixels held in the latch 103. The result of determination is sent out to a defective pixel correction block 106, where if that pixel is determined as defective, it is corrected into a correction output 107. Tuned clock signals CLK are entered in the latch 103, latch 103', normal pixel detection block 104, defective pixel detection block 105 and defective pixel correction block 106.